

SOCKET ASSEMBLY FOR TEST OF INTEGRATED CIRCUIT, AND ITS  
INTEGRATED CIRCUIT AND TESTER

ABSTRACT OF THE DISCLOSURE

5           A socket assembly for an integrated circuit test, and its  
integrated circuit and tester, are provided to select a direct  
or indirect connection of an integrated circuit to a test board.  
This configuration provides increased efficiency, and reduced  
load capacity through direct connection so as to increase  
10 reliability of an electrical characteristic test. The socket  
assembly includes a guide block, a guide part and a pressurizing  
plate. The guide block is in a terminal region of a test board,  
the guide block defining an area into which an integrated  
circuit can be inserted opposite terminals formed on the test  
15 board in the terminal region. The guide part is provided on an  
inner side wall of the guide block, to guide an insertion  
position of the integrated circuit so that respective leads of  
the integrated circuit are aligned with the corresponding  
terminals of the test board. The pressurizing plate is adapted  
20 to interface with the guide block, the pressurizing plate  
including a pressurizing protrusion on a surface thereof, such  
that when the pressurizing plate is applied to the guide block,  
the respective leads of the integrated circuit are urged to  
connect with the corresponding terminals of the test board.

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